

Search Notes

Application/Control No.

10/822,187

Examiner

Huy D. Nguyen

Applicant(s)/Patent under
Reexamination

AGRAWAL ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
455	414.3	5/18/2006	HN
	414.1		
	410		
	411		
	415		
	419		
	420		
	422.1		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East; Text search (USPAT, US-PGPUB, EPO, JPO, DERWENT). See search history printout.	5/18/2006	HN